

FDS6984S

Dual Notebook Power Supply N-Channel PowerTrench® SyncFET™

General Description

The FDS6984S is designed to replace two single SO-8 MOSFETs and Schottky diode in synchronous DC:DC power supplies that provide various peripheral voltages for notebook computers and other battery powered electronic devices. FDS6984S contains two unique 30V, N-channel, logic level, PowerTrench MOSFETs designed to maximize power conversion efficiency.

The high-side switch (Q1) is designed with specific emphasis on reducing switching losses while the low-side switch (Q2) is optimized to reduce conduction losses. Q2 also includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

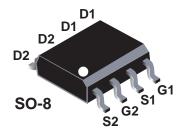
Features

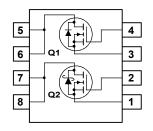
 Q2: Optimized to minimize conduction losses Includes SyncFET Schottky diode

8.5A, 30V
$$R_{DS(on)} = 19 \text{ m}\Omega @ V_{GS} = 10V$$
 $R_{DS(on)} = 28 \text{ m}\Omega @ V_{GS} = 4.5V$

 Q1: Optimized for low switching losses Low gate charge (5 nC typical)

5.5A, 30V
$$R_{DS(on)} = 0.040\Omega @ V_{GS} = 10V$$
 $R_{DS(on)} = 0.055\Omega @ V_{GS} = 4.5V$





Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Q2	Q1	Units	
V _{DSS}	Drain-Source Voltage	30	30	V	
V _{GSS}	Gate-Source Voltage	±20	±20	V	
I _D	Drain Current - Continuous	(Note 1a)	8.5	5.5	Α
	- Pulsed		30	20	
P _D	Power Dissipation for Dual Operation		2	2	W
	Power Dissipation for Single Operation	(Note 1a)	1.		
		1			
		(Note 1c)	0.	9	
T _J , T _{STG}	Operating and Storage Junction Temperat	ture Range	-55 to	+150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

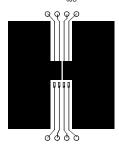
Device Marking	Device	Reel Size	Tape width	Quantity
FDS6984S	FDS6984S	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Chai	racteristics		•				
BV _{DSS}	Drain-Source Breakdown	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	Q2	30			V
	Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	Q1	30			
DSS	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q2 Q1			500 1	μΑ
GSSF	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V	All			100	nA
GSSR	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$	All			-100	nA
On Char	acteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 1 \text{ mA}$ $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	Q2 Q1	1		3	V
$\Delta V_{GS(th)}$	Gate Threshold Voltage	I _D = 1 mA, Referenced to 25°C	Q2		-6		mV/°C
ΔT_{J}	Temperature Coefficient	I _D = 250 uA, Referenced to 25°C	Q1		-4		
R _{DS(on)}	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 8.5 A V_{GS} = 10 V, I_D = 8.5 A, T_J = 125°C V_{GS} = 4.5 V, I_D = 7 A	Q2		16 24 23	19 32 28	mΩ
		$\begin{aligned} & V_{GS} = 4.5 \text{ V, } I_D = 7 \text{ A} \\ & V_{GS} = 10 \text{ V, } I_D = 5.5 \text{ A} \\ & V_{GS} = 10 \text{ V, } I_D = 5.5 \text{ A, } T_J = 125^{\circ}\text{C} \\ & V_{GS} = 4.5 \text{ V, } I_D = 4.6 \text{ A} \\ & V_{GS} = 10 \text{ V, } V_{DS} = 5 \text{ V} \end{aligned}$	Q1		35 53 48	40 60 55	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	Q2 Q1	30 20			Α
G FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 8.5 \text{ A}$ $V_{DS} = 5 \text{ V}, I_{D} = 5.5 \text{ A}$	Q2 Q1		26 40		S
Dynami	Characteristics						
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	Q2 Q1		1233 462		pF
Coss	Output Capacitance		Q2 Q1		344 113		pF
C _{rss}	Reverse Transfer Capacitance		Q2 Q1		106 40		pF
Switchir	ng Characteristics (Note 2			1			
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, I_D = 1 \text{ A}, V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	Q2 Q1		8 10	16 18	ns
t _r	Turn-On Rise Time	763 101, 16EN 0-1	Q2 Q1		5 14	10 25	ns
$t_{d(off)}$	Turn-Off Delay Time		Q2 Q1		25 21	40 34	ns
t_f	Turn-Off Fall Time		Q2 Q1		11 7	20 14	ns
Qg	Total Gate Charge	Q2 V _{DS} = 15 V, I _D = 8.5 A, V _{GS} =5V	Q2 Q1		11 8.5	16 12	nC
Q _{gs}	Gate-Source Charge	Q1	Q2 Q1		5 2.4		nC
Q _{qd}	Gate-Drain Charge	$V_{DS} = 15 \text{ V}, I_D = 5.5 \text{ A}, V_{GS} = 5 \text{ V}$	Q2		4		nC

Electrical Characteristics (continued) T_A = 25°C unless otherwise noted

Symbol	Parameter	Test Condit	Test Conditions			Тур	Max	Units	
Drain-Source Diode Characteristics and Maximum Ratings									
Is	Maximum Continuous Drain-Sc	rrent	Q2 Q1			3.0 1.3	А		
t _{rr}	1	I _F = 10A,		Q2		17		ns	
	Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$	(Note 3)			12.5		nC	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 3.5 \text{ A}$ $V_{GS} = 0 \text{ V}, I_{S} = 1.3 \text{ A}$	(Note 2) (Note 2)	Q2 Q1		0.5 0.74	0.7 1.2	V	

1. R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $\rm\,R_{\theta JC}$ is guaranteed by design while $\rm\,R_{\theta CA}$ is determined by the user's board design.



78°C/W when mounted on a 0.5in² pad of 2 oz copper



125°C/W when mounted on a 0.02 in² pad of 2 oz copper

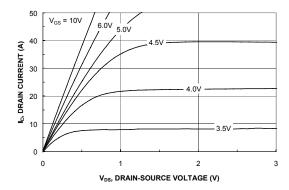


135°C/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

- 2. See "SyncFET Schottky body diode characteristics" below.
 3. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

Typical Characteristics: Q2

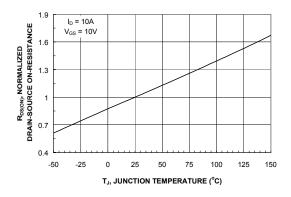


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Normalized Argonal Particles Argonal Partic

Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



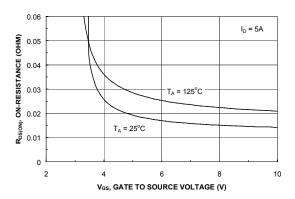
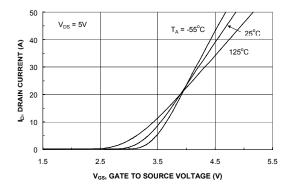


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



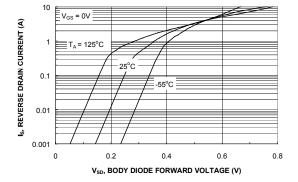
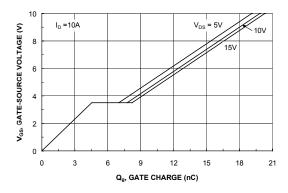


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q2



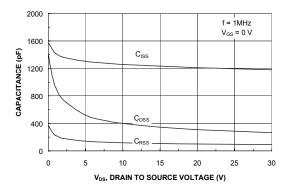
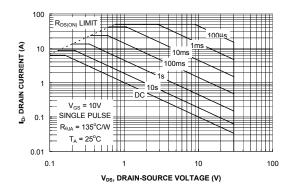


Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.



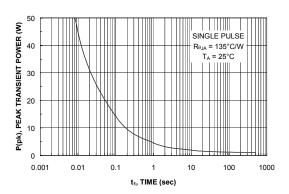


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

Typical Characteristics Q1

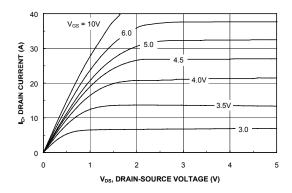
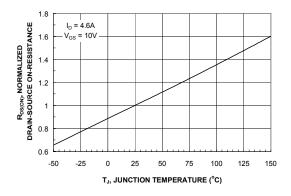


Figure 11. On-Region Characteristics.

Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.



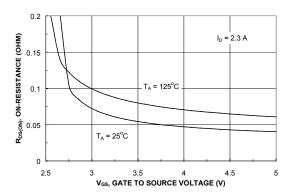
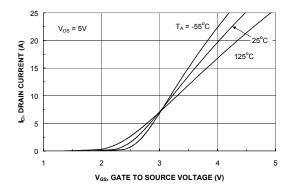


Figure 13. On-Resistance Variation with Temperature.

Figure 14. On-Resistance Variation with Gate-to-Source Voltage.



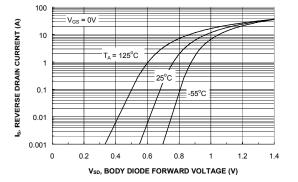
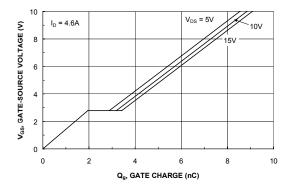


Figure 15. Transfer Characteristics.

Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics Q1



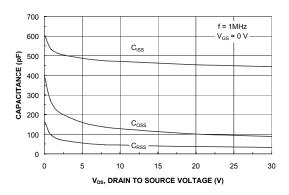


Figure 17. Gate Charge Characteristics.

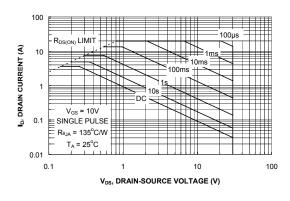


Figure 18. Capacitance Characteristics.

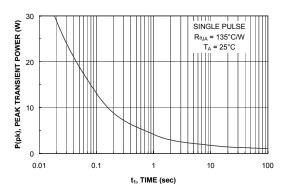


Figure 19. Maximum Safe Operating Area.



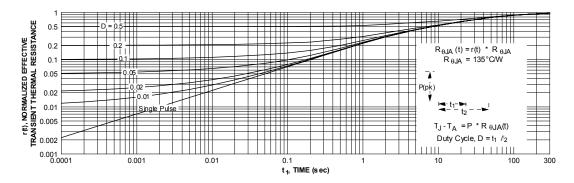


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 22 shows the reverse recovery characteristic of the FDS6984S.

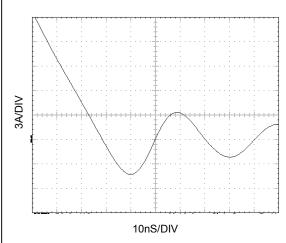


Figure 22. FDS6984S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 23 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6690A).

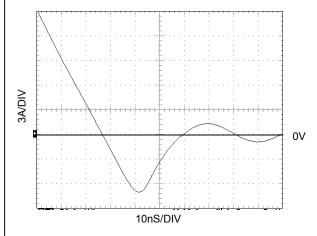


Figure 23. Non-SyncFET (FDS6690A) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

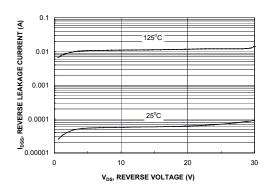
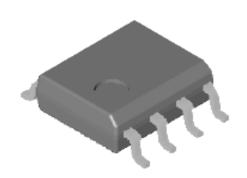


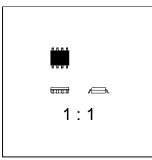
Figure 24. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

SOIC-8 Package Dimensions



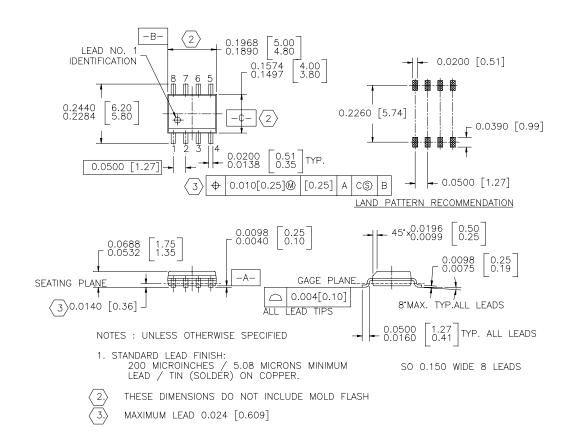
SOIC-8 (FS PKG Code S1)





Scale 1:1 on letter size paper
Dimensions shown below are in:
inches [millimeters]

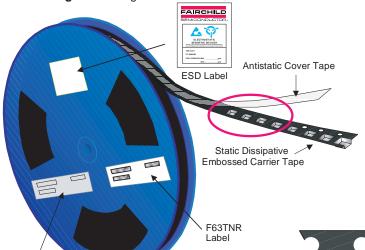
Part Weight per unit (gram): 0.0774



SOIC-8 Tape and Reel Data



SOIC(8lds) Packaging Configuration: Figure 1.0



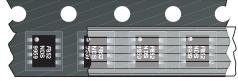
Packaging Description:

SOIC-8 parts are shipped in tape. The carrier tape is made from a dissipative (carbon filled) polycarbonate resin. The cover tape is a multilayer film (Heat Activated Adhesive in nature) primarily composed of polyester film, adhesive layer, sealant, and anti-static sprayed agent. These reeled parts in standard option are shipped with 2,500 units per 13° or 330cm diameter reel. The relea are dark blue in color and is made of polystyrene plastic (anti-static coated). Other option comes in 500 units per 7° or 177cm diameter reel. This and some other options are further described in the Packaging Information table.

These full reels are individually barcode labeled and placed inside a standard intermediate box (illustrated in figure 1.0) made of recyclable corrugated brown paper. One box contains two reels maximum. And these boxes are placed inside a barcode labeled shipping box which comes in different sizes depending on the number of parts shipped.

ESD Label

F63TN Label

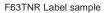




SOIC-8 Unit Orientation

343mm x 342mm x 64mm Standard Intermediate box

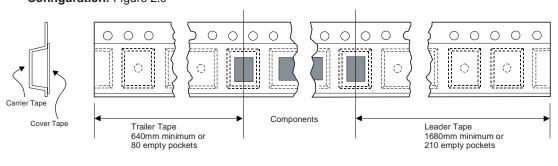
SOIC (8lds) Packaging Information Standard no flow code) **Packaging Option** L86Z F011 D84Z Rail/Tube TNR TNR Packaging type TNR Qty per Reel/Tube/Bag 2.500 95 4.000 500 Reel Size 13" Dia 13" Dia 7" Dia Box Dimension (mm) 343x64x343 530x130x83 343x64x343 184x187x47 Max qty per Box 5,000 30,000 8,000 1,000 Weight per unit (gm) 0.0774 0.0774 0.0774 0.0774 0.1182 Weight per Reel (kg) 0.6060 0.9696 Note/Comments



Customized Label



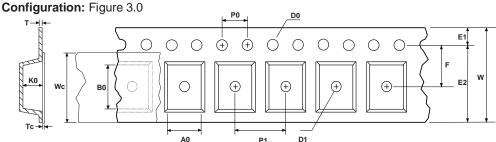
SOIC(8lds) Tape Leader and Trailer Configuration: Figure 2.0



F63TNI



SOIC(8lds) Embossed Carrier Tape



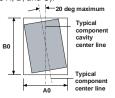


	Dimensions are in millimeter													
Pkg type	Α0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
SOIC(8lds) (12mm)	6.50 +/-0.10	5.30 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.60 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	2.1 +/-0.10	0.450 +/- 0.150	9.2 +/-0.3	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation



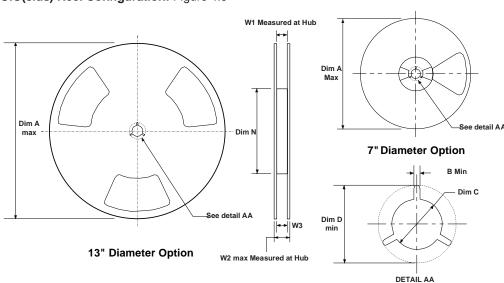
Sketch B (Top View)

Component Rotation



Sketch C (Top View)
Component lateral movement

SOIC(8lds) Reel Configuration: Figure 4.0



Dimensions are in inches and millimeters									
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	2.165 55	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

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CoolFET™ GTO™ QT Optoelectronics™

CROSSVOLT™ HiSeC™ Quiet Series™ DOME™ ISOPLANAR™ SuperSOT™-3 E²CMOSTM MICROWIRE™ SuperSOT™-6 OPTOLOGIC™ EnSigna™ SuperSOT™-8 FACT™ OPTOPLANAR™ SyncFET™ POP™ FACT Quiet Series™ TinyLogic™

FAST® PowerTrench® UHC™

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- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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